

4-2-3-2-input AND-OR-invert gate

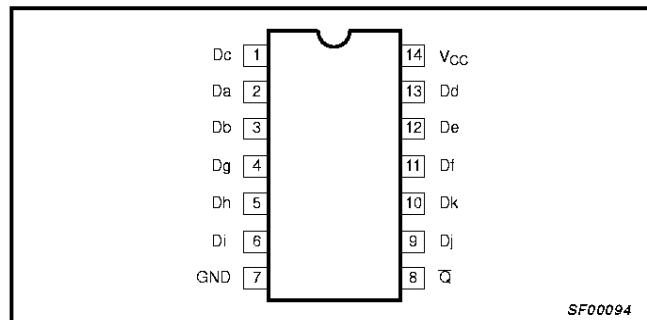
74F64

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F64	4.0ns	2.5mA

ORDERING INFORMATION

DESCRIPTION	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$, $T_{amb} = 0^\circ C$ to $+70^\circ C$	PKG. DWG. #
14-pin plastic DIP	N74F64N	SOT27-1
14-pin plastic SO	N74F64D	SOT108-1

PIN CONFIGURATION

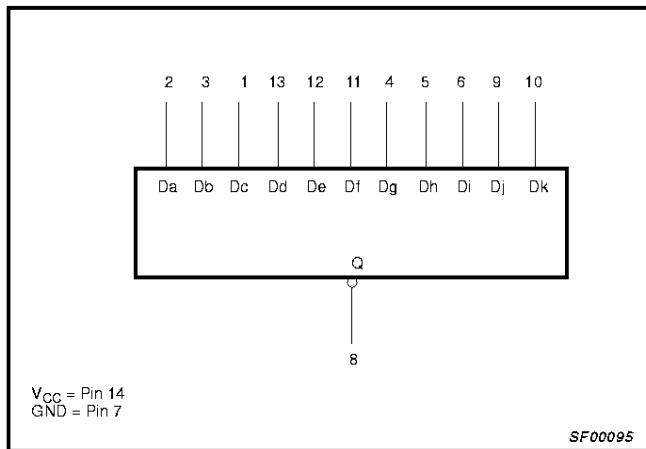


INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

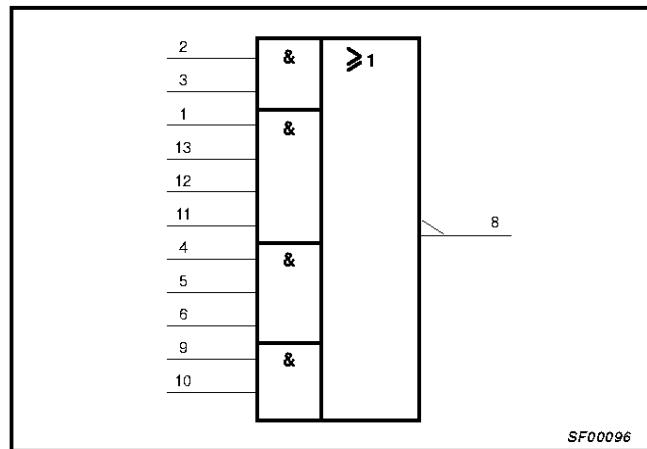
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Dn	Data inputs	1.0/1.0	20µA/0.6mA
\overline{Q}	Data output	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

LOGIC SYMBOL

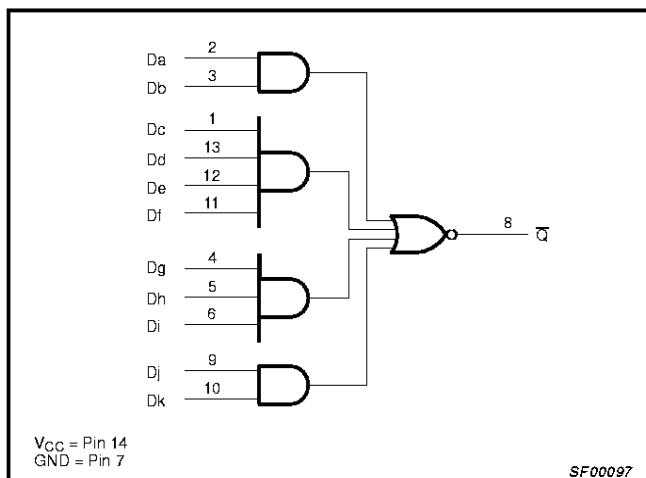


IEC/IEEE SYMBOL



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LOGIC DIAGRAM**FUNCTION TABLE**

INPUTS												OUTPUT
D _a	D _b	D _c	D _d	D _e	D _f	D _g	D _h	D _i	D _j	D _k	Q-bar	
H	H	X	X	X	X	X	X	X	X	X	L	
X	X	H	H	H	H	X	X	X	X	X	L	
X	X	X	X	X	X	H	H	H	X	X	L	
X	X	X	X	X	X	X	X	X	H	H	L	
All other combinations												H

NOTES:

1. H = High voltage level
2. L = Low voltage level
3. X = Don't care

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device.
Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	-0.5 to V _{CC}	V
I _{OUT}	Current applied to output in Low output state	40	mA
T _{amb}	Operating free-air temperature range	0 to +70	°C
T _{stg}	Storage temperature range	-65 to +150	°C

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RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
V _{IL}	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-1	mA
I _{OL}	Low-level output current			20	mA
T _{amb}	Operating free-air temperature range	0		+70	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹		LIMITS			UNIT	
				MIN	TYP ²	MAX		
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IL} = MAX	±10%V _{CC}	2.5			V	
		V _{IH} = MIN, I _{OH} = MAX	±5%V _{CC}	2.7	3.4			
V _{OL}	Low-level output voltage	V _{CC} = MIN, V _{IL} = MAX	±10%V _{CC}		0.30	0.50	V	
		V _{IH} = MIN, I _{OL} = MAX	±5%V _{CC}		0.30	0.50		
V _{IK}	Input clamp voltage	V _{CC} = MIN, I _I = I _{IK}			-0.73	-1.2	V	
I _I	Input current at maximum input voltage	V _{CC} = MAX, V _I = 7.0V				100	µA	
I _{IH}	High-level input current	V _{CC} = MAX, V _I = 2.7V				20	µA	
I _{IL}	Low-level input current	V _{CC} = MAX, V _I = 0.5V				-0.6	mA	
I _{OS}	Short-circuit output current ³	V _{CC} = MAX		-60		-150	mA	
I _{CC}	Supply current (total)	I _{CCH}	V _{CC} = MAX	V _{IN} = GND		1.9	2.8	mA
		I _{CCL}		V _{IN} = 4.5V		3.1	4.7	

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
2. All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

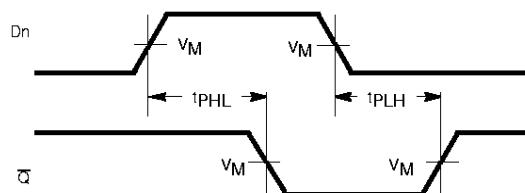
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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT	
			$V_{CC} = +5.0V$			$V_{CC} = +5.0V \pm 10\%$			
			MIN	TYP	MAX	MIN	MAX		
t_{PLH}	Propagation delay Dn to Q	Waveform 1	2.5 2.0	4.6 3.2	6.0 4.5	2.5 2.0	7.0 5.5	ns	

AC WAVEFORMS

For all waveforms, $V_M = 1.5V$.

SF00098

Waveform 1. Propagation Delay for Inverting Outputs

TEST CIRCUIT AND WAVEFORM

